



YEA SHIN TECHNOLOGY CO., LTD

YS60P03BA

## P-Channel Enhancement MOSFET



**VDS= -30V, ID= -60A**

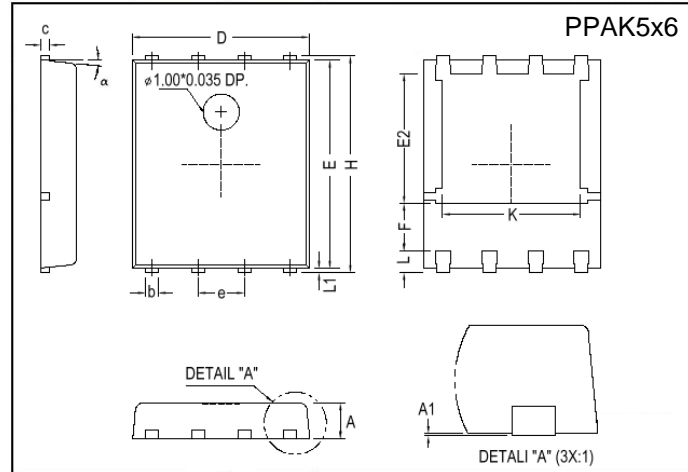
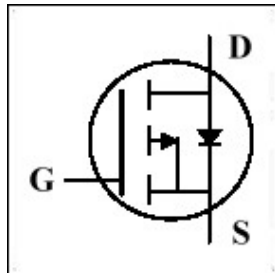
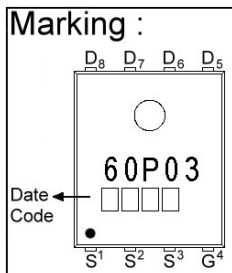
### DESCRIPTION

The YS60P03BA is using trench DMOS technology. This advanced technology has been especially tailored to minimize  $R_{DS(ON)}$  provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

The YS60P03BA meet the RoHS and Green Product requirement, 100% EAS and Rg guaranteed with full function reliability approved.

### FEATURES

- Advanced DMOS Trench technology
- Suit for -4.5V Gate Drive Application
- Green Device Available
- Fast switching
- 100% EAS and Rg Guaranteed



REF.	Millimeter			REF.	Millimeter		
	Min.	Nom.	Max.		Min.	Nom.	Max.
A	0.85	1.00	1.15	E	5.70	-	5.90
A1	0.00	-	0.10	e	-	1.27	-
b	0.30	-	0.51	H	5.90	-	6.20
c	0.20	-	0.30	L	-	0.60	-
D	4.80	-	5.00	L1	0.06	-	0.20
F	1.10REF.			$\alpha$	0°	-	12°
E2	3.50REF.			K	3.70	3.90	4.10

### Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>1</sup>	$I_D$ @ $T_C=25^\circ C$	-60	A
	$I_D$ @ $T_C=100^\circ C$	-38	A
Pulsed Drain Current <sup>1,2</sup>	$I_{DM}$	-240	A
Total Power Dissipation <sup>4</sup>	$P_D$ @ $T_C=25^\circ C$	96	W
	$P_D$ @ $T_A=25^\circ C$	2	W
Single Pulse Avalanche Energy, $L=0.1mH^3$	$E_{AS}$	168	mJ
Single Pulse Avalanche Current, $L=0.1mH^3$	$I_{AS}$	-58	A
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 ~ +150	$^\circ C$

### Thermal Data

Parameter	Symbol	Conditions	Max. Value	Unit
Thermal Resistance Junction-ambient <sup>1</sup>	$R_{\theta JA}$	Steady State	62.5	$^\circ C/W$
Thermal Resistance Junction-case <sup>1</sup>	$R_{\theta JC}$	Steady State	1.3	$^\circ C/W$

# DEVICE CHARACTERISTICS

## YS60P03BA

### Electrical Characteristics (T<sub>j</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-30	-	-	V	V <sub>GS</sub> =0, I <sub>D</sub> =-250uA
Gate Threshold Voltage	V <sub>GS(th)</sub>	-1.2	-1.6	-2.5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250uA
Forward Transconductance	g <sub>fs</sub>	-	14	-	S	V <sub>DS</sub> =-10V, I <sub>D</sub> =-10A
Gate-Source Leakage Current	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> = ±20V
Drain-Source Leakage Current(T <sub>j</sub> =25°C)	I <sub>DSS</sub>	-	-	-1	uA	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0
Drain-Source Leakage Current(T <sub>j</sub> =125°C)		-	-	-10	uA	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0
Static Drain-Source On-Resistance <sup>2</sup>	R <sub>DS(ON)</sub>	-	7.2	8.5	mΩ	V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A
		-	11.5	14		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-16A
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	-	35	-	nC	I <sub>D</sub> =-10A V <sub>DS</sub> =-15V V <sub>GS</sub> =-4.5V
Gate-Source Charge	Q <sub>gs</sub>	-	10.8	-		
Gate-Drain ("Miller") Change	Q <sub>gd</sub>	-	10.6	-		
Turn-on Delay Time <sup>2</sup>	T <sub>d(on)</sub>	-	24.5	-	ns	V <sub>DD</sub> =-15V I <sub>D</sub> =-1A V <sub>GS</sub> =-10V R <sub>G</sub> =6Ω
Rise Time	T <sub>r</sub>	-	10.5	-		
Turn-off Delay Time	T <sub>d(off)</sub>	-	157	-		
Fall Time	T <sub>f</sub>	-	50	-		
Input Capacitance	C <sub>iss</sub>	-	3300	-	pF	V <sub>GS</sub> =0V V <sub>DS</sub> =-15V f=1.0MHz
Output Capacitance	C <sub>oss</sub>	-	410	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	280	-		

### Guaranteed Avalanche Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Single Pulse Avalanche Energy <sup>5</sup>	EAS	20	-	-	mJ	V <sub>DD</sub> =-25V, L=0.1mH, I <sub>AS</sub> =-20A

### Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Forward On Voltage <sup>2</sup>	V <sub>SD</sub>	-	-	-1.2	V	V <sub>GS</sub> =0V, I <sub>S</sub> =-20A, T <sub>J</sub> =25°C
Continuous Source Current <sup>1,6</sup>	I <sub>S</sub>	-	-	-60	A	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current
Pulsed Source Current <sup>2,6</sup>	I <sub>SM</sub>	-	-	-120	A	

Notes: 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 20Z copper.

2. The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.

3. The EAS data shows Max. rating. The test condition is V<sub>DD</sub>=-25V, V<sub>GS</sub>=-10V, L=0.1mH, I<sub>AS</sub>=-58A.

4. The power dissipation is limited by 150°C junction temperature.

5. The Min. value is 100% EAS tested guarantee.

6. The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

# DEVICE CHARACTERISTICS

## YS60P03BA

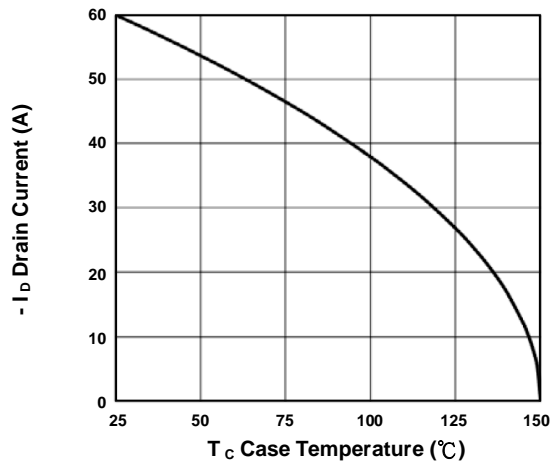


Fig.1 Drain Current vs.  $T_C$

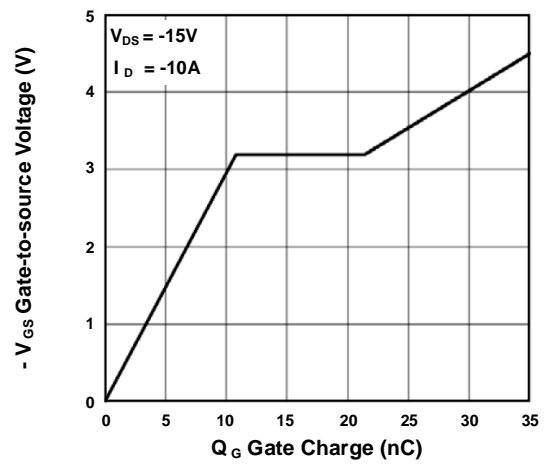


Fig.2 Gate Charge Characteristics

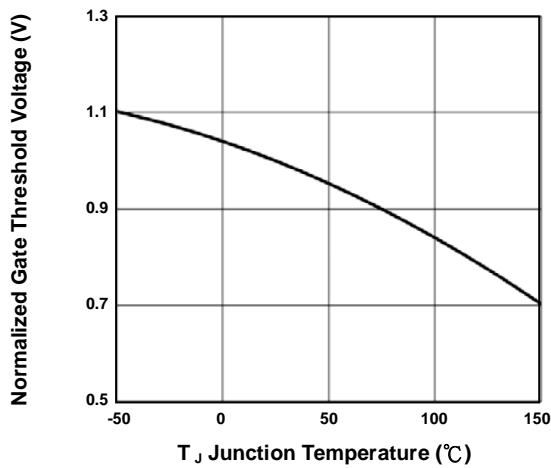


Fig.3 Normalized  $V_{GS(th)}$  vs.  $T_J$

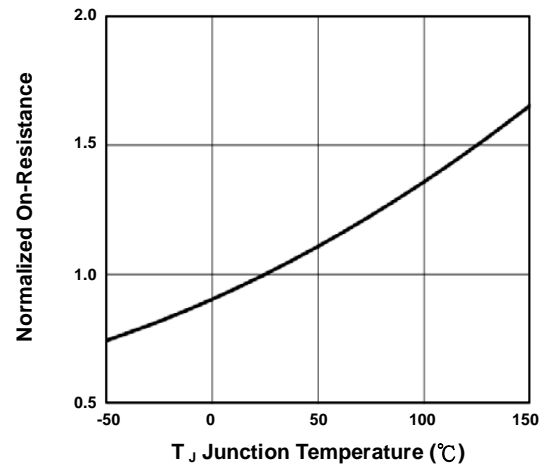


Fig.4 Normalized  $R_{DS(on)}$  vs.  $T_J$

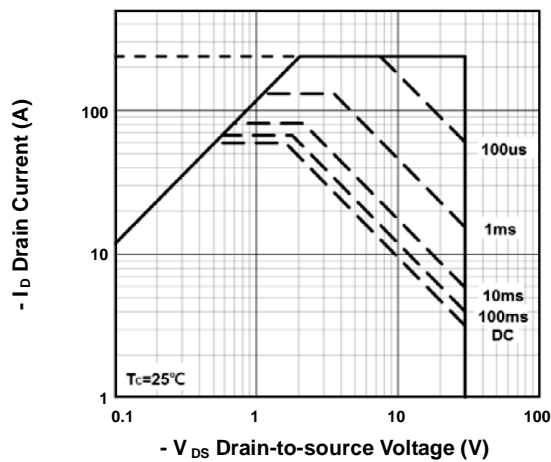


Fig.5 Safe Operating Area

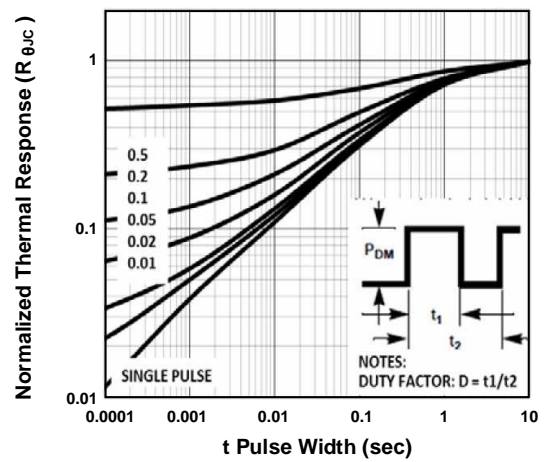


Fig.6 Transient Thermal Impedance

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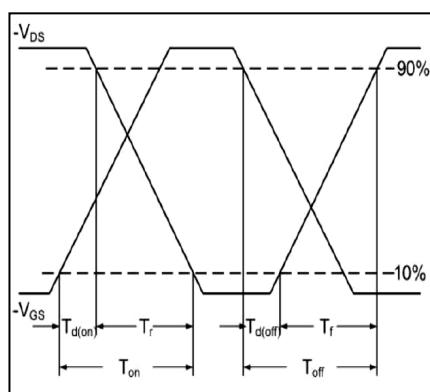


Fig.7 Switching Time Waveform

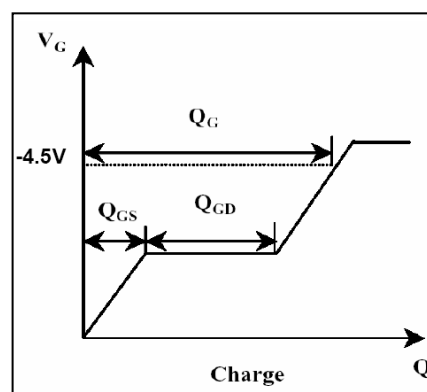


Fig.8 Gate Charge Waveform